

DATA SHEET



# EMX-1434

"SMART' PXI EXPRESS 4-CHANNEL 204.8 KSA/S ARBITRARY WAVEFORM GENERATOR

### APPLICATIONS

Modal / GVT (Ground Vehicle Testing)
Acoustics
Shock / Vibration
Rotational Machinery
Electronic Test

### FEATURES

### **Analog Performance**

- 4-channel, 204.8 k Sa/s sample rate per channel
- · Dual integrated tach input channels
- Synchronized DSA source
- Rotational measurement capability
- 4 channel DIO
- Advanced system-on-a-chip filtering and analysis
- Precision multi-channel synchronization
- End-to-end internal source self-calibration

### System Level Functionality

- Corporate Wide Cloud Data Management / Access
- · Comprehensive Runtime Health Monitoring
- Run-time Self-calibration / Embedded NIST Calibration
- Precision Distributed Measurement Synchronization
- Data Streaming at Full Acquisition Rates on all Channels across PXI Express backplane

### Software

- X-Modal III
- EXLab
- · SO Analyzer
- Open Source Drivers

Specifications contained within this document are subject to change without notice



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# **OVERVIEW**

### High Performance Architecture

The EMX-1434 is an arbitrary source/tach high performance modular PXIe board which has four channels arbitrary sources and two channels tachometer inputs. It is uniquely designed for sound/vibration and DSA applications and can be easily synchronized with digitized data giving the capability to combine the required source and signal analysis into one single chassis to maximize flexibility. It supports various output modes such as Sine, Burst Sine, Chirp, Burst-random and continuous random. It also provides two 64-bit tachometer/counter input channels each of which has a 16k-word FIFO. The module functions as a high-performance arbitrary waveform generator that is also ideal for electronic test applications requiring standard function generator capability, or the need to generate custom-defined waveforms.

With its capability of providing stimulus to a shaker, loudspeaker and other electrical devices, it can be paired with the EMX-4250, EMX-4350, EMX-4380 and EMX-6010 products forming the basis for a versatile dynamic signal analysis system. With the most advanced PXIe and LXI architecture, it can stream numerous waveforms from the host computer to the module, with that ability to synchronize multiple channels in a distributed architecture through the use of IEEE-1588 precision time protocol. Analog Performance

### **Analog Performance**

### Built-in Sine and Noise Waveforms

Sine waveform is one of the most common test waveforms. The EXM-1434 provides four independent channels of sine wave capability, each with its own frequency, phase, and amplitude. Sine waves can be generated in continuous and burst modes with frequencies from less than 1Hz to 93 kHz.

The EMX-1434's noise capabilities are specifically designed to provide periodic and pseudo random waveforms in either continuous or burst mode. Additionally, the EMX-1434 can band-translate the noise to have a non-zero start frequency. This allows the user to pinpoint the noise stimulus to frequencies of interest, avoiding troublesome resonances or frequencies that might damage the device under test.

### **Arbitrary Waveform**

The EMX-1434 can generate arbitrary waveforms to provide simulate virtually any stimulus pattern with a bandwidth up to 80 kHz. Arbitrary waveforms can be downloaded from the host computer and then output a repeating loop. Or the host can continuously download new segments of a waveform to be concatenated with previous segments, allowing continuous, glitch-free playback of any length waveform.

### 24-bit Resolution for dynamic range

The EMX-1434 has a 24-bit DAC per channel and a very high -115dB spurious free dynamic range. The 24-bit DAC ensures superior accuracy and allows the EMX-1434 to output high-fidelity waveforms. The -115dB SFDR maximizes the dynamic performance of the EMX-1434 and is useful for applications where there is a need for smooth output levels over a wide amplitude range.

## Analog Performance

### Built-in Tachometer inputs for Rotating Machinery/Order Analysis Tests

The EMX-1434 has integrated dual tachometer inputs with signal conditioning for a wide range of Tach input signals. These inputs allow tight integration of tachometer information from rotating machinery with acquired data from a digitizer card. This provides the information the floating point processor needs to do RPM triggering of order analysis measurements. Data accuracy can be increased by the fact that the measurement data can be re-sampled and synchronized based on the edge of the tachometer. With the build-in tachometer feature, the EMX-1434 works best with the EMX series DSA products, EMX-4250, EMX-4350, EMX-4380 and EMX-6010 in stimulus and response applications such as rotating machinery and order analysis tests.

### Channel independence and pairing

The EMX-1434 four output channels are grouped in pairs. Both channels of a pair must output the same type of waveform - sine, random or arbitrary. But each pair of channels is completely independent from the other pair. For example, one channel pair can output two uncorrelated random noise signals while the other channel pair and produce two independent sine waves.

### Graceful Shutdown/Safety Feature

Since arbitrary sources can drive very expensive devices under test, it is important to provide an orderly shutdown in case of emergency. In addition to programmable ramp-up and ramp-down rates, the arbitrary source has a smooth ramp-down from AC power failure, or in response to its emergency shutdown input. Furthermore, the EMX-1434 supports < 4 ms fast shutdown for failure conditions and < 5 sec slow shutdown which would be typically used for shaker applications.

### **Analog Performance**

#### Built-in self calibration

Measurement accuracy is maximized utilizing a unique approach for run-time self-calibration eliminating the need to disconnect transducers or field connections. Complete end-to-end self-calibration is performed using a precise onboard voltage reference source permitting execution at test time, at current temperature. This approach not only delivers the most accurate measurements possible, but also validates the instrumentation signal path prior to test.

Complete embedded NIST traceable calibration eliminates the need to remove the instrument from service, resulting in maximum test equipment utilization, reduced need for spares, and reduced down time. The embedded web interface provides a fool-proof, easy to use interface to permit complete traceable calibration, in place, without removing the instrument from service.

### System-level Functionality

Industry standard MATLAB® and Simulink® design tools simplify implementation, maximize re-usability, and provide access to hundreds of standard filters and analysis algorithms.

### System-level Functionality

Corporate wide cloud data management delivers advanced data access, security and storage services throughout the organization, accessible from web browsers and other applications, on desktop and mobile devices.

- · Simplified, next generation user data services
- Corporate wide data access and security
- · Dynamically scalable data management services
- · Accessible on a wide range of traditional and mobile devices
- · Eliminates need for knowledge of the physical location or configuration of the system

Comprehensive runtime health monitoring (BIST: Built-in Self-test) provides test system confidence and peace of mind by ensuring that the complete instrumentation measurement path is functional and delivering the most accurate results possible.

- · Ensures runtime instrument performance and accuracy
- · Performed without disconnecting external transducer cabling
- · Delivers exceptional run-time convenience and measurement confidence
- · Instrument performance is verified utilizing precision internal voltage references

Precision distributed measurement synchronization ensures that all test data is time correlated whether the instrumentation is centrally located in the laboratory or distributed around a test article.

- · Enables widely distributed system level performance
- Utilizes embedded IEEE 1588 precision time protocol
- Precise synchronization across multiple instrumentation modules and chassis
- · Synchronization achieved over-the-wire (Ethernet), with complete user transparency

### Software

### Software

Open-source SDRL X-Modal III experimental modal analysis software features intuitive task oriented user interfaces, extensive modal parameter estimation algorithms, parallel display capabilities, flexible data management, and unparalleled channel expandability.

- MATLAB®-based open-source programming environment
- Multiple live parameter estimation windows displayed in parallel
- Task oriented, easy-to-use user interface always "one-click" away
- · Simplified "cut & paste" data management and unit's unification tool

EXLab is an easy to use, turn-key, data acquisition solution featuring intelligent configuration capabilities, automatic device discovery, extensive time and frequency domain data visualization, and post-acquisition display and analysis tools.

- · Intuitive setup and control
- · Remote client monitor and control
- · Advanced filtering, analysis, and modeling
- Waterfall, video, images, scatter, 3D model and SRS diagrams

Open Source industry standard, drivers and programming interfaces provide the flexibility and freedom of choice to select the application programming environment best suited for the application and specific development requirements.

- Support for all major programming environments
- · Software interoperability, maintainability, and reusability
- · Common development environment and interface across all instrumentation types

### General Specifications

#### **SOURCE**

**OUTPUT MODES** 

DIGITAL-TO-ANALOG CONVERTER OVERVOLTAGE PROTECTION

DYNAMIC RANGE

THD

CROSS CHANNEL PHASE MATCH CROSS CHANNEL AMP MATCH

SAMPLING RATE FLATNESS

PHASE LINEARITY

CROSSTALK

MAXIMUM AMPLITUDE
OUTPUT IMPEDANCE
MAXIMUM OUTPUT CURRENT
MAXIMUM CAPACITIVE LOAD

RESIDUAL DC OFFSET

AMPLITUDE CONTROL

AMPLITUDE RANGE
AMPLITUDE SCALE FACTOR
AMPLITUDE RAMP-DOWN TIME

SINE OUTPUT MODE

SHUTDOWN

SINE FREQUENCY

FREQUENCY RESOLUTION AMPLITUDE ACCURACY

GENERATED FREQUENCY ACCURACY

NOISE OUTPUT MODE

FREQUENCY SPANS

PASSBAND FLATNESS
CREST FACTOR
PERCENT IN-BAND ENERGY

MINIMUM SPAN

CENTER FREQUENCY RESOLUTION

Sine, burst sine, pseudo random noise, and band translation. Arbitrary

waveform with loop or continuous output and burst

Independent 24-bit per channel

±40 V peak

115 dB, 0-51.2 k Hz spurious free

-98 dB, to 20 kHz ±0.01° per 1 kHz

±0.01 dB 10Hz to 20 kHz

204.8 kSa/s

±0.01 dB to 35 kHz ±0.06 dB 35 kHz to 93 kHz

±0.005° DC to 10kHz ±0.02° 10 kHz to 30 kHz

 $\pm 0.5^{\circ}$  30 kHz to 93 kHz  $^{-100}$  dB to 10 kHz

-95 dB 10 kHz to 93 kHz

±10 V <0.5 Ω ±25 mA

Aberrations begin at 20nF

Overshoot and ringing but no oscillation at  $1\mu F$ 

<±1mV

-20 dB to 0 dB in 1dB steps

0 to 1 4 ms

yes

0.01 Hz to 93 kHz

71 uHz ±0.05 dB

Clock source dependent; internal clock 50ppm.

80 KHz or 51.2 KHz Full Span – with/without Decimated by 5 and/or Decimated by 2 with

maximum of 16 times

< 1.2dBpp 4:1 (Typical)

> 90% (Typical) Full Span / (5\*2<sup>16</sup>)

71 uHz

FREQUENCY AND BAND TRANSLATION	MIN SPAN	MAX SPAN	MAX CENTER FREQUENCY
FS = 204.8 KHZ	0.244140625 Hz	80 KHz	80 KHz
FS = 131.072 KHZ	0.15625 Hz	51.2 KHz	51.2 KHz

### General Specifications

### ARBITRARY OUTPUT MODE

MAXIMUM SIGNAL BANDWIDTH 80 KHz or 51.2KHz

BUFFER SIZE 64K Samples x 2 Buffers

CONTINUOUS ARB DATA RATE

User must supply data @ rate =  $F/(5^m)^*(2^n)$ 

Where Fs=204.8KHz or 131.072KHz

m = 0 or 1n = 0,1,2... 16

2 kΩ

2

CONSTANT LEVEL OUTPUT

OUTPUT LEVEL AT 1 KHZ  $\pm 10$ V peak RESIDUAL DC OFFSET  $<\pm 1$ mV

SUMMER INPUT

MAXIMUM INPUT ±10V peak

GAIN, SUMMER INPUT TO SIGNAL OUTPUT 1

INPUT IMPEDANCE

**TACHOMETER** 

INPUTS

FREQUENCY INPUT RANGE 1 MHz RANGES  $\pm 25 \text{ V}$   $\pm 250 \text{ V}$ 

INPUT TYPE Differential INPUT COUPLING DC, AC 0.6 Hz
MINIMUM PULSE WIDTH 600 nS

THRESHOLD Programmable ±95% of range
HYSTERESIS Programmable ±1% of range

DIGITAL I/O

 CHANNELS
 4

 VIN HIGH
 3.5 V min

 VIN LOW
 1.5V max

VOUT HIGH  $4.9 \text{ V} - \text{lout} * 100 \Omega$   $\text{VOUT LOW} \\ \text{OVERVOLTAGE PROTECTION} \\ \pm 15 \text{ V} \text{ peak}$ 

OVERVOLIAGE PROTECTION  $\pm 15 \text{ V pc}$ MAX SLEW RATE 50 V/µs

SHUTDOWN INPUT A normally open contact between GND (SMB shell) and a

38 k $\Omega$  resistor pulled up to +5 V (SMB center).

Note: that this is not a safety rated shutdown and that if a safety rated shutdown is required then the user is responsible for such, not VTI Instruments.

### Mechanical Specifications

#### **IEEE 1588 CLOCK SPECIFICATIONS**

CLOCK OSCILLATOR ACCURACY SYNCHRONIZATION ACCURACY TIMESTAMP ACCURACY RESOLUTION

#### IFFF 1588-BASED TRIGGER TIMING

ALARM

TRIGGER TIME ACCURACY
TIME TO TRIGGER DELAY

RECEIVE LAN [0-7] EVENT
TRIGGER TIME ACCURACY
TIME TO TRIGGER DELAY
Future timestamp
Past/zero timestamp

#### HARDWARF TRIGGER TIMING

DIO BUS

TIME TO TRIGGER DELAY

As good as time synchronization down to 50 ns

50 ns

25 ns

±50 ppm

As good as time synchronization down to 50 ns

As good as time synchronization down to 50 ns

Reports "synchronized" when < ±100 ns of the 1588 master clock

50 ns typical 1 ms maximum

57 ns typical

### **Environmental Specifications**

TEMPERATURE OPERATING

STORAGE
RELATIVE HUMIDITY

KELATIVE HUIVIIDIT

ALTITUDE

SHOCK AND VIBRATION RANDOM VIBRATION

SINUSOIDAL

SHOCK

0 °C to +50 °C

-40 °C to +70 °C

5% - 95% (non-condensing)

3000 m

Conforms to MIL-PRF-28800F

10 Min per Axis, MIL-PRF-28800F Class 3

5 to 55hz Resonance Search per MIL-PRF-28800F Class 3, each Axis

30g/Axis, 11mS half Sine pulse per MIL-PRF-28800F Class 3  $\,$ 

### Notes:

- 1) All specifications are typical unless otherwise stated as a minimum or maximum.
- 2) All specifications subject to change without notice.
- 3) All specifications assume within 24 hours and 5°C of self-calibration temperature unless otherwise specified.

# **Ordering Information**

EMX-1434 4-Channel, 204.8 kSa/s Smart Arbitrary Waveform Source

SOFTWARE

X-MODAL III Modal Analysis Software

SO ANALYZER Acoustics/Impact/Rotational/Shock Software

EXLAB\* General Purpose DAQ Software

\*Multiple configurations available

RELATED PRODUCTS

EMX-4350 4-Channel, 625k Sa/s Smart Dynamic Signal Analyzer
EMX-4250 16-Channel, 204.8k Sa/s Smart Dynamic Signal Analyzer

EMX-4251 8-Channel, 204.8k Sa/s DSA Digitizer

EMX-4008 8-Channel, BNC adapter
EMX-4016 16-Channel, BNC adapter

RELIABLE DATA FIRST TIME EVERY TIME